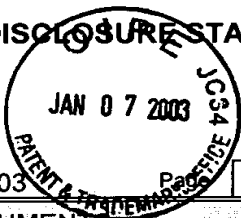


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INFORMATION DISCLOSURE STATEMENT
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Date: January 7, 2003 Page 1 of 1

Applicant: Fukuyama
Appln. No.: 09/917,839
Filing Date: July 31, 2001
Examiner: Unassigned Group Art Unit: Unassigned

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
20	AR 5,120,953	06/1992	Harris	250	227.20	
	BR					
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
	JR							
	KR							
	LR							
	MR							
	NR							
	OR							
	PR							
	QR							
	RR							
	SR							

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

20	TR	Davidovits et al., "SCANNING LASER MICROSCOPE," Nature, Vol. 223, (August 23, 1969), 1 page			
20	UR	Juškaitis, et al.; "SEMICONDUCTOR LASER CONTROL MICROSCOPY," Applied Optics, Vol. 33, No. 4 (1 February, 1994), pp. 578-584.			
20	VR	Fujita et al.; "LASER FEEDBACK MICROSCOPY CONTROLLING THE LASER OSCILLATION OF SEMICONDUCTOR LASER REENTERED LIGHT," Laser Study, Vol. 24, No. 10 (October, 1996), pp1084-1090.			x
	WR				
	XR				
	YR				

Examiner *[Signature]*

Date Considered: 9/23/03

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.